

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10580513	MAHE, PHILIPPE
	<b>Examiner</b>	<b>Art Unit</b>
	SHEELA C CHAWAN	2624

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	100,249,118,232,248,249,276,286,291,154,181,190,195,203.	4/6/09	SCC
250	370.08, 370.09	"	"
376	178, 245, 251, 153, 156	"	"
358	1.9,1.1,500,501,502,518,520,1.18	"	"
378	378/\$.CCLS.	"	"

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY.	4/6/09	SCC
INVENTOR NAME SEARCH.	"	"
382/100,249,118,232,248,249,276,286,291,154,181,190,195,203.ccls.	"	"
358/1.9,1.1,500,501,502,518,520,1.18.ccls.	"	"
376/178,245,251,153,156, 249,.CCLS.	"	"
250/ 370.08, 370.09, 559.2.CCLS.	"	"
378/\$.CCLS.	"	"
INTERFERENCE SEARCH	11/1/09	SCC
SEARCH IEE E OR INSPEC DATA BASE.	11/1/09	SCC
SEARCH UP-DATE	11/1/09	SCC

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	100,141	11/1/09	SCC
376	249	11/1/09	SCC
250	370.09	11/1/09	SCC

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